

Preparation and Characterization of Organic Thin Films

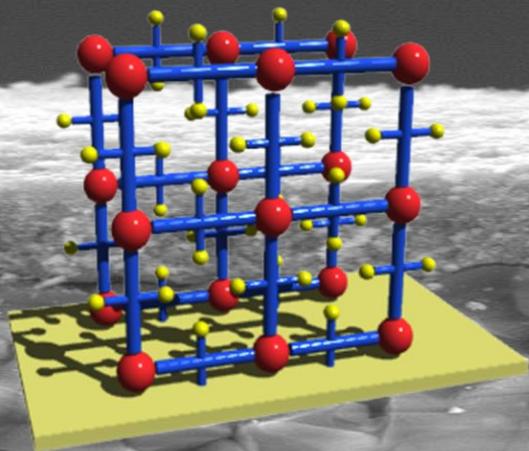
When: Mo., 22.7.2024 – Fr., 26.7.2024, 9:15 a.m. – 12:30 p.m. (daily) +
afternoon session on appointment

Where: CN / Building 330 / Room 356 (theoretical part)

The course is designed for advanced students with a Bachelor in chemistry. Different methods for the preparation and structuring of organic thin films on metal and oxidic surfaces as well as different techniques for the (site-selective) surface characterization will be discussed. The theoretical introduction in the morning will be followed by a practical part in the afternoon. The course will be given in English language.

Please register via ILIAS (event number 5250)

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Topics

- Self-Assembled Monolayers (SAMs)
- Surface-Anchored Metal-Organic Frameworks (SURMOFs)
- Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS)
- Atomic Force Microscopy (AFM)
- (FT-)IR and Raman Spectroscopy
- X-Ray Diffractometry (XRD)
- X-Ray Photoelectron Spectroscopy (XPS)
- Quartz Crystal Micro Balance (QCM) gravimetry
- Ellipsometry